Search Notes

Application/Control No.	Applicant(s)/Patent Reexamination	under
10/528,739	SENESCHAL ET A	AL.
Examiner	Art Unit	
Richard Chan	2618	

SEARCHED					
Class	Subclass	Date	Examiner		
455	71		•		
455	203				
455	46				
455	202				
455	265				
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
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